

PCN# : P1C2A Issue Date : Jan. 10, 2012

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

Expected First Shipment Date for Changed Product : Apr. 09, 2012

Expected First Date Code of Changed Product :1212

Last Date for Shipment of Unchanged Product : Apr. 09, 2012

Description of Change (From) :

High voltage high speed power switch application NPN transistors fabricated at Fairchild Korea.

Description of Change (To) :

High voltage high speed power switch application NPN transistors fabricated at an alternative fabrication facility located in China.

Reason for Change:

This change is being made to increase production capacity and provide better supply chain flexibility. Other similar Fairchild products have previously been qualified and are being produced in this alternate fabrication facility. Affected products will be fully compliant to all published data sheet specifications and package outline drawings. Quality and reliability will remain at the highest standards already demonstrated with Fairchild's existing products. If you require data or samples to evaluate this change, please contact Fairchild Semiconductor within 30 days of receipt of this notification. Unnecessary delays in requesting data or samples may limit Fairchild's ability to provide a continuous supply of product. This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild sales representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.



Affected Product(s):

BD675AS	BD677AS	BD677ASTU	
BD679AS	BD679ASTU	BD681S	
BD681STU	BDX53C	BDX53CTU	
BU406	BU406TU	BU407	
FJD5555TM	FJP5555ATU	FJP5555STU	
FJP5555TU	KSD1692YS	KSD560RTSTU	
KSD560RTU	KSD560YTU	KSE13009FTU	
KSE13009LTU	KSE13009TU	KSE800STU	
KSH112TM	KSH122ITU	KSH122TF	
KSH122TM	KSH41CTF	MJD112TF	
MJD122TF	MJD41CTF	MJE800STU	
TIP110	TIP110TU	TIP111TU	
TIP112	TIP112TU	TIP120	
TIP120TU	TIP120TU_F129	TIP121	
TIP121TU	TIP122	TIP122TU	
TIP122TU_F129	TIP41A	TIP41B	
TIP41C	TIP41CTU	TIP41CTU_F129	

Qualification Plan	Device	Package	Process	No. of Lots
Q10110124	BU406TU	TO220	HP BJT	2

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Reverse Bias	125C, 80% BV	JESD22-A108	168, 300 hrs	0/154
Temperature Humidity Bias Test	85C, 85%RH, 10V	JESD22- A101B	168, 300 hrs	0/154
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/154
Power cycles	Delta Tj of 100, 5 min on, 5 min off	JESD22-A105	8572cycles	0/154
RSDH	270'C,15S	JESD22-B106		0/60

Qualification Plan	Device	Package	Process	No. of Lots
Q10110124	KSD1692YS	TO126	HP BJT	1

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Reverse Bias	125C, 80% BV	JESD22-A108	168, 300 hrs	0/77
Temperature Humidity Bias Test	85C, 85%RH, 10V	JESD22- A101B	168, 300 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
Power cycles	Delta Tj of 100, 5 min on, 5 min off	JESD22-A105	8572cycles	0/77
RSDH	270'C,15S	JESD22-B106		0/30

Qualification Plan	Device	Package	Process	No. of Lots
Q10110124	KSE13009F	TF220	HP BJT	1

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Reverse Bias	125C, 80% BV	JESD22-A108	168, 300 hrs	0/77
Temperature Humidity Bias Test	85C, 85%RH, 10V	JESD22- A101B	168, 300 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
Power cycles	Delta Tj of 100, 5 min on, 5 min off	JESD22-A105	8572cycles	0/77
RSDH	270'C,15S	JESD22-B106		0/30

Qualification Plan	Device	Package	Process	No. of Lots
Q10110124	KSH122ITU	TO251	HP BJT	2

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Reverse Bias	125C, 80% BV	JESD22-A108	168, 300 hrs	0/154
Temperature Humidity Bias Test	85C, 85%RH, 10V	JESD22- A101B	168, 300 hrs	0/154
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/154
Power cycles	Delta Tj of 100, 2 min on, 2 min off	JESD22-A105	8572cycles	0/154
RSDH	270'C,15S	JESD22-B106		0/60

Qualification Plan	Device	Package	Process	No. of Lots
Q10110124	FJD5555TM	T0252	HP BJT	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/154
High Temperature Reverse Bias	125C, 80% BV	JESD22-A108	168, 300 hrs	0/77
Temperature Humidity Bias Test	85C, 85%RH, 10V	JESD22- A101B	168, 300 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
Power cycles	Delta Tj of 100, 2min on, 2 min off	JESD22-A105	8572cycles	0/77
RSDH	270'C,15S	JESD22-B106		0/30